

A look to Charge carrier properties in single-crystal diamonds using the Allpix-squared simulation framework

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Simulation Flow







Modules







- transfer data between modules
- store the simulation results in to file





Data Transfer b/t Modules



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Goal: to check the validity of diamond as sensor material **Why Diamond?**

Diamond's advantages as sensor material in HEP

- Low Atomic Number ideal for tracking detectors but low signal
- 43 eV Displacement energy Radiation hard
- High drift velocities Fast Signal Readout

Property	Diamond	Silicon	
Band Gap (ev)	5.5	1.12	Low Noise
Atomic Number (<i>z</i>)	6	14	Low Signal
Displacement Energy (<i>ev/atom</i>)	43	13 – 20	Radiation Hard
Mobility (cm^2/Vs)	1900 (<i>e</i>), 2300 (<i>h</i>)	1350(e)480(h)	Fast Signal
Saturation Velocity ($10^7 cm/s$)	1 . 3 (<i>e</i>), 1 . 7 (<i>h</i>)	1.1(e), 0.8(h)	Fast Signal
Aver. Signal Created/100 um (e)	3602	8892	Low Signal





Applications in HEP

- LHC (CERN) [1] and CDF (Collider Detector at Fermilab) [2] use diamond sensors for beam monitoring and accident Protection. ATLAS BCM/BLM, CMS BCM/BCM-F
- LHCb BCM
- ATLAS Diamond Beam Monitor (DBM)
- Inner layer?



Marko Mikuz: Diamond Sensors



Diamond Validity Check

• Same drift velocity and mobility output for Diamond and silicon





ToF or TCT

- A simple single-crystal CVD sensor sandwiched between two metallic electrodes
- metal-insulator-metal (MIM) detector

$$V_{drift} = \frac{d}{t} = \frac{L}{\tau}$$
$$V_{drift} = \mu(E)E$$
$$L = \mu E\tau$$

• the important parameters

$$\mu, \tau$$
 and $\mu\tau$



Schematic diagram of a MIM

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Simulation Code

- Detector Type: Monolithic pixel scCVD
- Detector Size: (3mm × 3mm) × 400um
- Mobility Model: Jacobani Canali
- Energy Source: Am-241 Alpha source
- Energy Deposited: 5.486 MeV

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Detector Simulation: Left: top view, Right side view





• Get saturates at around 10E7 cm/s after 30000 V/cm



Electron Drift Velocities



Silicon Drift Velocity

- Electrons: 7000 V/cm, 0.766 cm/s
- Holes: 12000 V/cm, 0.467 cm/s

Projection Propagation





Silicon e & h Drift Velocity

- Electrons: 7000 V/cm, 0.766 cm/s
- Holes: 12000 V/cm, 0.467 cm/s

Projection Propagation



Look for an ad-hoc thickness in agreement with experimental data 200um, 7000 V/cm, 1.46 cm/s 130um, 7000 V/cm, 1.06 cm/s 100um, 7000 V/cm, 0.766 cm/s equivalent Thickness 1.00E+08

Silicon Drift Velocity

1.00E+07 Drift Velocity (cm/s) - Velocity (cm/s) 200um 1.00E+06 velocity (cm/s) 130um Velocity (cm/s) 100um 1.00E+05 1.00E+04 0 10000 20000 30000 40000 50000 60000





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Electron Drift Velocity 1 30000 20000 40000 50000 60000 70000 80000 Drift Velocity (cm/s) 10E7 0.1



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Generic Propagation







Silicon Drift Velocity

 Generic propagation gives higher drift velocity values but allows customised models



Generic Propagation Vs Projection Propagation



Silicon Mobilities

 Constant low field mobilities below 1000 V/cm round about 1500 cm²/Vs

Projection Propagation





Silicon Mobilities

- Electrons: 1488 cm^2/Vs
- Holes: 441 cm^2/Vs

Projection Propagation





Silicon Mobilities

• Generic Propagation predicts higher values





Caughey Model for Diamond

• Huge variation of parameters for diamond

Generic Propagation

$$v_{\rm drift} = v_{\rm sat} \frac{E/E_c}{(1 + (E/E_c)^\beta)^{1/\beta}}$$

Parameters	E_c (kV/cm)	μ_0 $(\mathrm{cm}^2/\mathrm{Vs})$	eta
e_{exp}	4.325 ± 0.731	14948 ± 8303	0.26 ± 0.06
h_{exp}	5.836 ± 0.251	2615 ± 148	0.90 ± 0.09
e_{lit}	5.779 ± 0.772	4551 ± 500	0.42 ± 0.01
h_{lit}	5.697 ± 0.529	2750 ± 70	0.81 ± 0.01

IEKP-KA/2017-19



Diamond Drift Velocity

- Much lower than predicted **1.3** -**2.63**(*e*) ,**1.57**-**1.7**(*h*) ٠
- Choice of right parameters ٠

Generic Propagation



Electric Field (cm/s)

Drift Velocity (cm/s)



Diamond Mobility

- Prediction of lower mobilities
- Needs more work

Generic Propagation





- Mobility vs temperature for (A) electrons (B) holes
- Shows significant variations for electron mobility





- The general trend is followed in the case of mobility and drift velocity.
- Some scaling is needed for either time, thickness, or electric field.
- The addition of Diamond specific parameters for the Caughy Model is needed



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- Some scaling is needed for either time, thickness, or electric field.
- The addition of Diamond specific parameters for the Caughy Model is needed

Thank You



CERN Example

Backup

The ATLAS Diamond Beam Monitor

Designed to measure the instantaneous luminosity, the background rates, and the beam spot position.

- Single DBM module: 18 mm × 21 mm pCVD diamond 500 µm thick instrumented with an FE-I4 pixel chip.
- 26,880 pixels: in 80 columns on 250 µm pitch and 336 rows on 50 µm pitch. This fine granularity provides high-precision particle tracking.
- charge collection distance of 200-220 μm at an applied bias voltage of 500 V.

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Marko Mikuz: Diamond Sensors

Jacobani Canali Mobility Model for Silicon Canali Model for Correction to the first one Hamburg or Klanner-Scharf Model for high ohmic <100> Silicon Masetti Model for carrier concentration in arsenic-, phosphorus-, and boron-doped Silicon MasettiCanali Model (Extended Canali Model) for charge carriers in Silicon Arora Model for concentration and temperature in Silicon RuchKino Model for transport properties of GaAs Quay Model for Germanium Levinshtein Model for GaN **Constant Mobility Model** Custom Mobility Model

Example:

Charge Career Mobility [Generic Propagation]

Implemented Models:

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https://gitlab.cern.ch/allpix-squared/allpix-squared/-/blob/master/src/physics/Mobility.hpp

Current Models in Allpix-Squared technische universität

Backup

6.2.1 Jacoboni-Canali Model From Allpix-Squared Manual

The Jacoboni-Canali model [36] is the most widely used parametrization of charge carrier mobility in Silicon as a function of the electric field E. It has originally been derived for $\langle 111 \rangle$ silicon lattice orientation, but is widely used also for the common $\langle 100 \rangle$ orientation. The mobility is parametrized as

$$\mu(E) = \frac{v_m}{E_c} \frac{1}{\left(1 + (E/E_c)^{\beta}\right)^{1/\beta}},\tag{6.1}$$

where v_m , E_c , and β are phenomenological parameters, defined for electrons and holes respectively. The temperature dependence of these parameters is taken into account by scaling them with respect to a reference parameter value as

$$A = A_{ref} \cdot T^{\gamma} \tag{6.2}$$

where A_{ref} is the reference parameter value, T the temperature in units of K, and γ the temperature scaling factor.

The parameter values implemented in $Allpix^2$ are taken from Table 5 of [36] as:

$$\begin{aligned} v_{m,e} &= 1.53 \times 10^9 \cdot T^{-0.87} \,\mathrm{cm/s} & v_{m,h} &= 1.62 \times 10^8 \cdot T^{-0.52} \,\mathrm{cm/s} \\ E_{c,e} &= 1.01 \cdot T^{1.55} \,\mathrm{V/cm} & E_{c,h} &= 1.24 \cdot T^{1.68} \,\mathrm{V/cm} \\ \beta_e &= 2.57 \times 10^{-2} \cdot T^{0.66} & \beta_h &= 0.46 \cdot T^{0.17} \end{aligned}$$

for electrons and holes, respectively.

This model can be selected in the configuration file via the parameter mobility_model = "jacoboni".



	$E_{\rm c}$ (kV/cm)	$V_{\rm sat}$ (cm/s)	β
electrons	5.779	2.63×10^{7}	0.42
	± 0.772	$\pm 0.2 imes 10^7$	± 0.01
holes	5.697	1.57×10^{7}	0.81
	± 0.529	$\pm 0.14 \times 10^7$	± 0.01

Backup

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Backup



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